Applied Physics Laboratory
IV.: Scanning Electron Microscopy

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Abstract

On the fourth occasion of the *Applied Physics Laboratory* we've learned the basic of the usage of a scanning electron microscope (SEM). The nature of this lecture was purely informative, where we didn't have any complex calculation or measurement task, besides a very short one. Our objective was to learn, how to set up the SEM, to take somewhat higher-quality pictures, which could be further analysed if needed.

I. INTRODUCTION

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mLab partners

APPENDIX A. – FIGURES

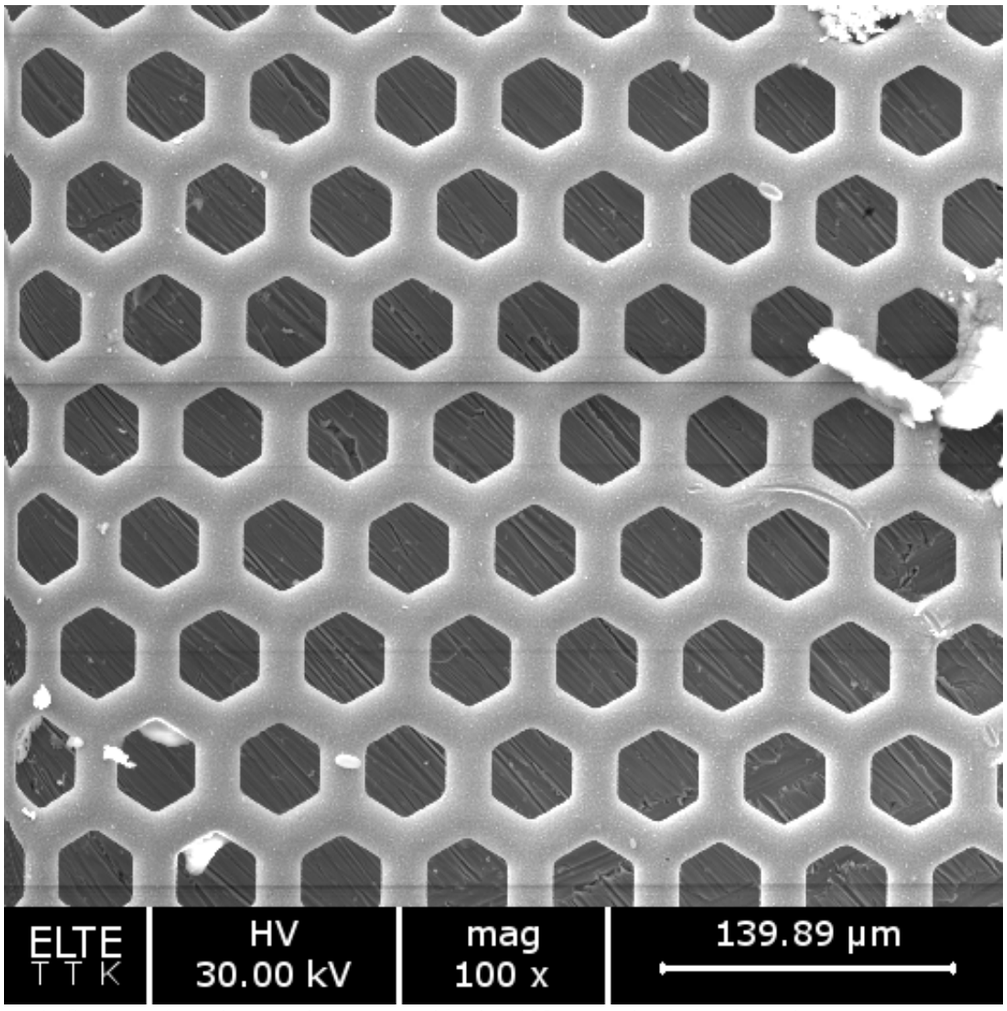

Figure 1: Surface of a microscopic copper grid with 100x magnitude by detecting secondary electrons.

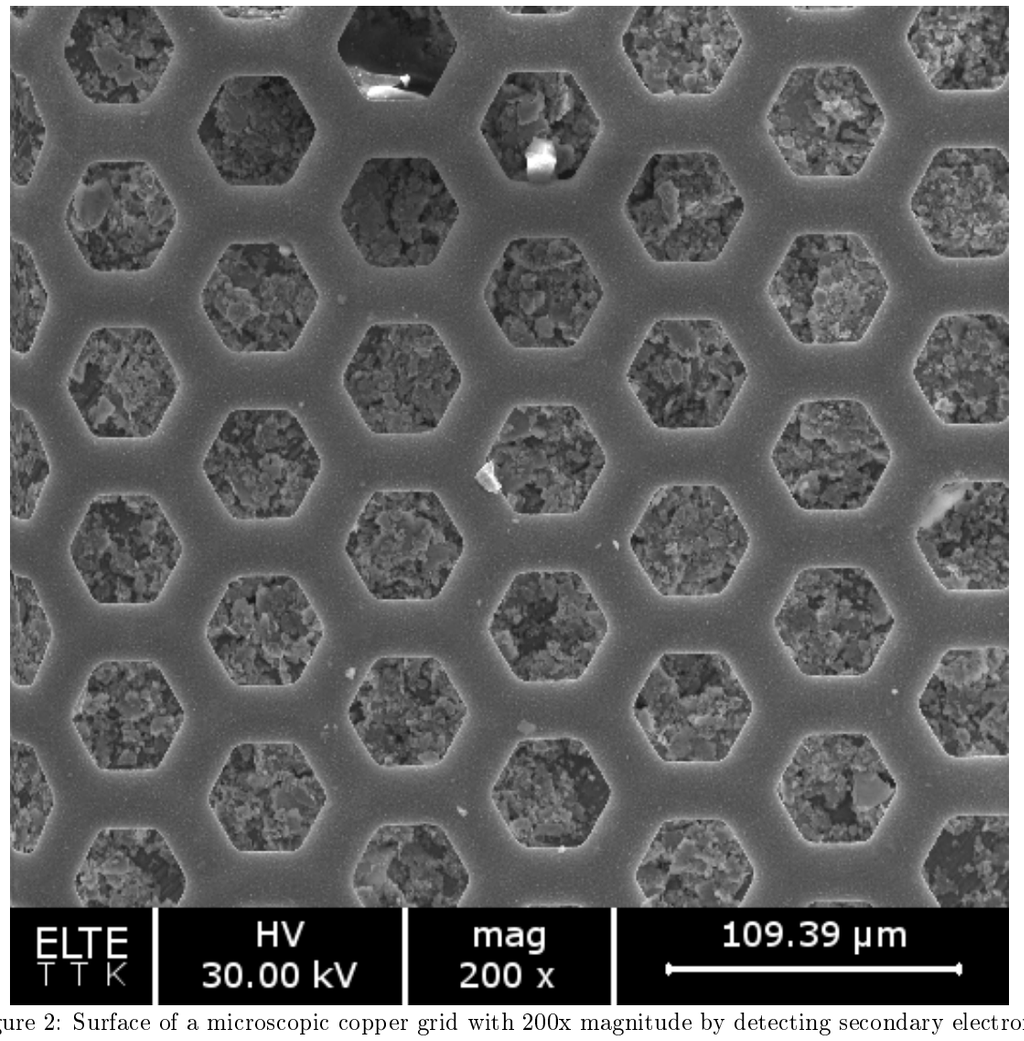

Figure 2: Surface of a microscopic copper grid with 200x magnitude by detecting secondary electrons.

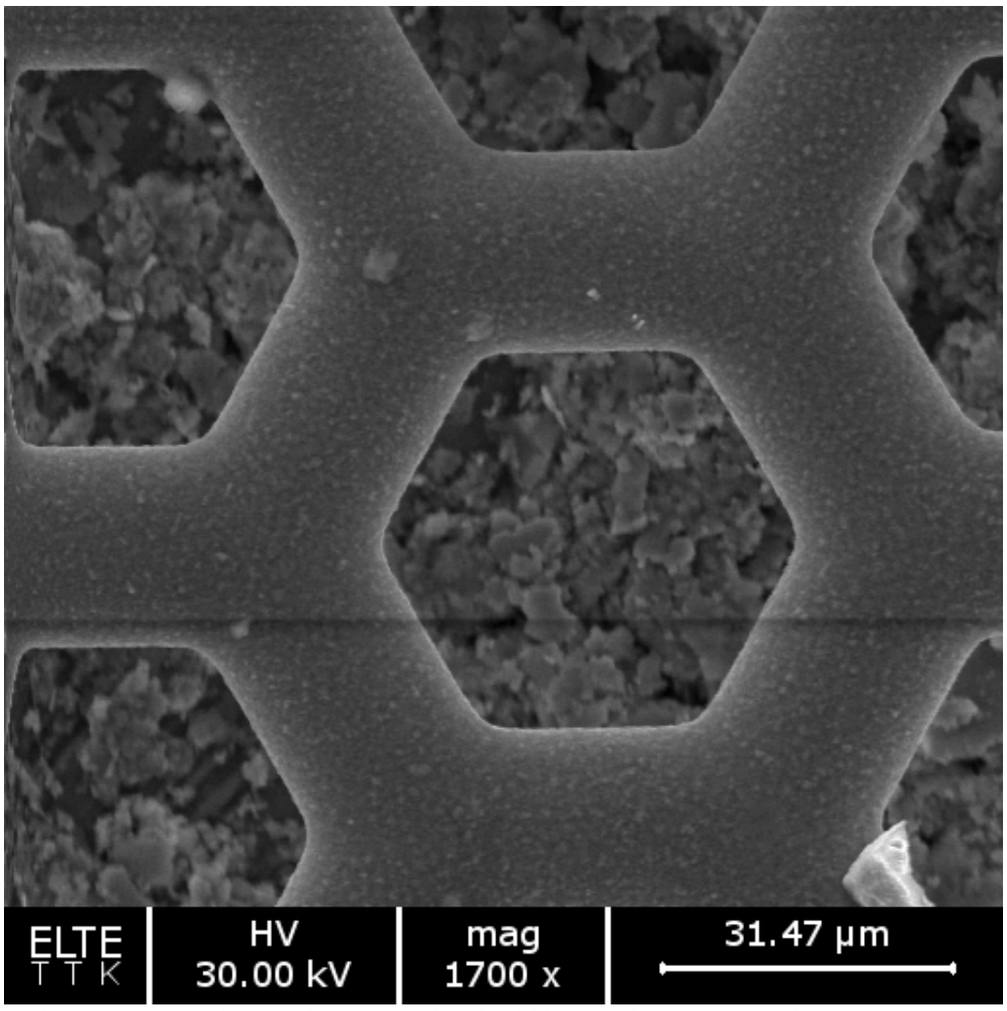

Figure 3: Surface of a microscopic copper grid with 700x magnitude by detecting secondary electrons.

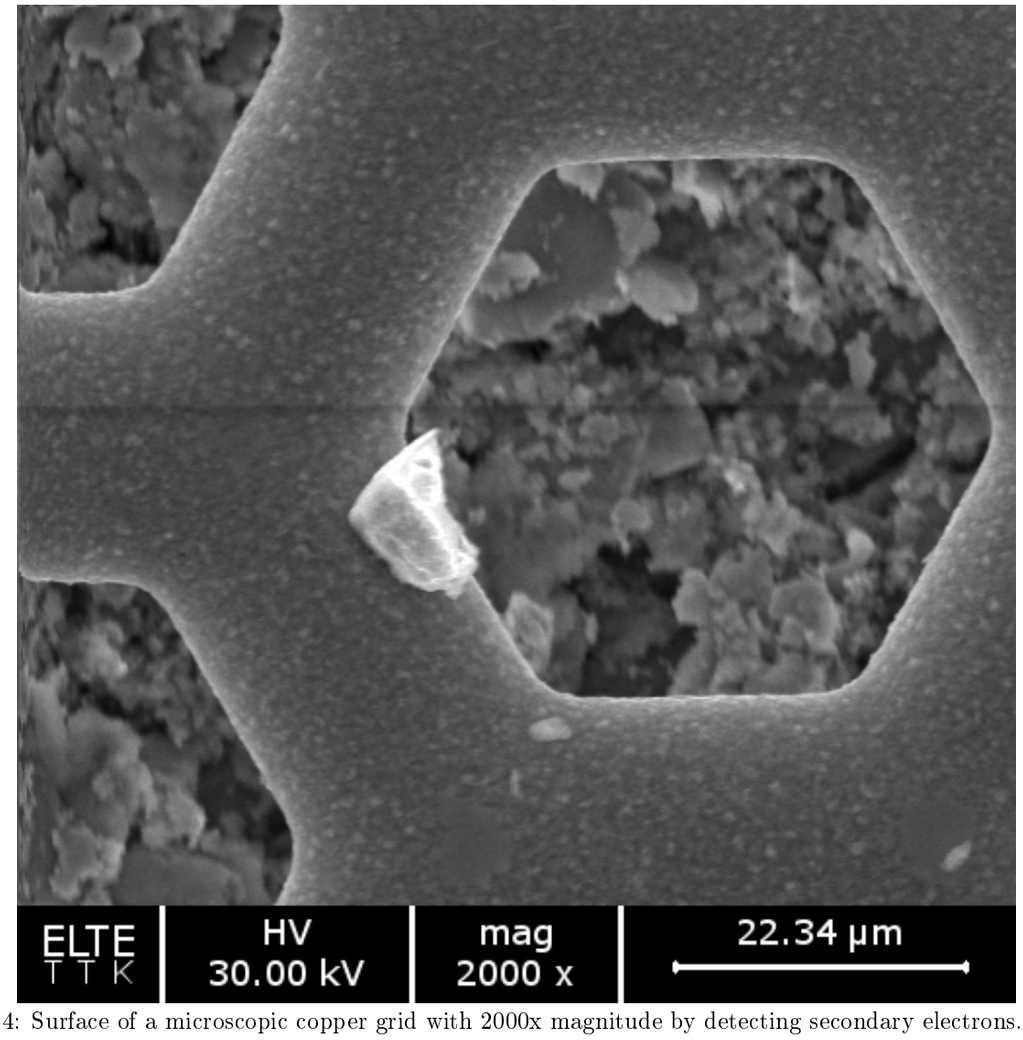

Figure 4: Surface of a microscopic copper grid with 2000x magnitude by detecting secondary electrons. On the copper grid also some contamination could be seen.